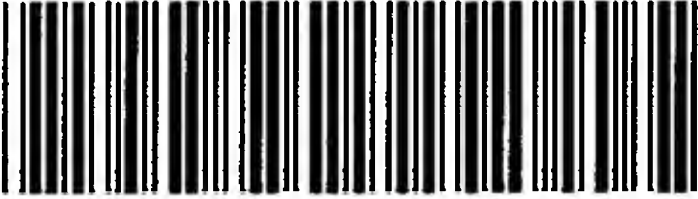


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/708,835	BEENAU ET AL.	
	Examiner	Art Unit	
	Nam V. Nguyen	2635	

SEARCHED			
Class	Subclass	Date	Examiner
340	5.53	11/28/2005	NN
340	5.2	11/28/2005	NN
340	5.4+	11/28/2005	NN
340	5.52	11/28/2005	NN
340	5.6	11/28/2005	NN
340	5.8+	11/28/2005	NN
340	10.1	11/28/2005	NN
340	10.4-10.5	11/28/2005	NN
235	379	11/28/2005	NN
235	380	11/28/2005	NN
235	492	11/28/2005	NN
705	35,54,76	11/28/2005	NN
705	186,194	11/28/2005	NN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East Search: USPAT; US-PUB; EPO;JPO and Derwent.	11/28/2005	NN